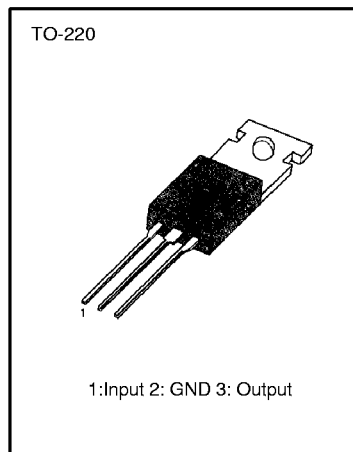


3-TERMINAL 0.5A POSITIVE VOLTAGE REGULATORS

The LM78MXXC/I series of three-terminal positive regulators are available in the TO-220 package with several fixed output voltages making it useful in a wide range of applications.

FEATURES

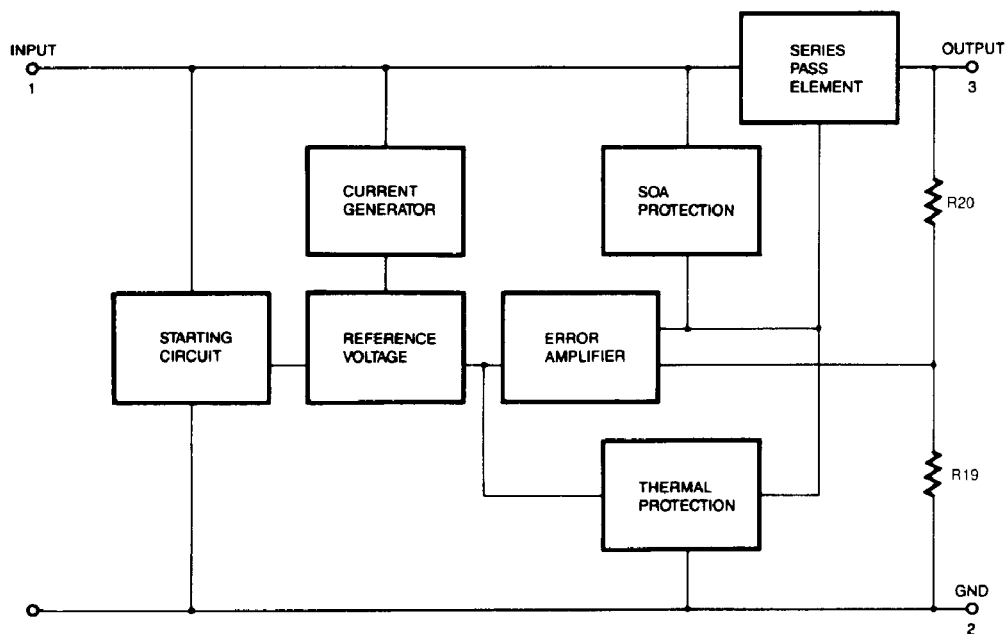
- Output Current up to 0.5A
- Output Voltages of 5; 6; 8; 10; 12; 15; 18; 20; 24V
- Thermal Overload Protection
- Short Circuit Protection
- Output Transistor SOA Protection
- Industrial and commercial temperature range



ORDERING INFORMATION

Device	Package	Operating Temperature
LM78MXXT	TO-220	0 ~ +125°C
LM78MXXIT	TO-220	- 40 ~ +125°C

BLOCK DIAGRAM



FAIRCHILD
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Rev. B

Characteristic	Symbol	Value	Unit
Input Voltage (for $V_O = 5V$ to $18V$)	V_I	35	V
(for $V_O = 24V$)	V_I	40	V
Thermal Resistance Junction-Cases	R_{EJC}	5	$^{\circ}C/W$
Thermal Resistance Junction-Air	R_{EJA}	65	$^{\circ}C/W$
Operating Temperature Range KA78XXI	T_{OPR}	-40~ + 125	$^{\circ}C$
KA78XX		0~ + 125	$^{\circ}C$
Storage Temperature Range	T_{STG}	-65~ + 150	$^{\circ}C$

LM78M05/I ELECTRICAL CHARACTERISTICS

(Refer to the test circuits, $T_{MIN} = T_J = 125^{\circ}C$, $I_O = 350mA$, $V_I = 10V$, unless otherwise specified, $C_I = 0.33\mu F$, $C_O = 0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J = 25^{\circ}C$	4.8	5	5.2	V
		$I_O = 5$ to $350mA$ $V_I = 7$ to $20V$	4.75	5	5.25	
Line Regulation	ΔV_O	$I_O = 200mA$ $T_J = 25^{\circ}C$			100	mV
		$V_I = 7$ to $25V$ $V_I = 8$ to $25V$			50	
Load Regulation	ΔV_O	$I_O = 5mA$ to $0.5A$, $T_J = 25^{\circ}C$			100	mV
		$I_O = 5mA$ to $200mA$, $T_J = 25^{\circ}C$			50	
Quiescent Current	I_Q	$T_J = 25^{\circ}C$		4.0	6	mA
Quiescent Current Change	ΔI_Q	$I_O = 5mA$ to $350mA$			0.5	mA
		$I_O = 200mA$ $V_I = 8$ to $25V$			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O = 5mA$ $T_J = 0$ to $125^{\circ}C$		- 0.5		mV/ $^{\circ}C$
Output Noise Voltage	V_N	$f = 10Hz$ to $100KHz$		40		μV
Ripple Rejection	RR	$f = 120Hz$, $I_O = 300mA$ $V_I = 8$ to $18V$	62			dB
Dropout Voltage	V_D	$T_J = 25^{\circ}C$, $I_O = 500mA$		2		V
Short Circuit Current	I_{SC}	$T_J = 25^{\circ}C$, $V_I = 35V$		300		mA
Peak Current	I_{PK}	$T_J = 25^{\circ}C$		700		mA

* T_{MIN} T_J T_{MAX}

LM78MXXI: $T_{MIN} = -40^{\circ}C$, $T_{MAX} = +125^{\circ}C$

LM78MXX: $T_{MIN} = 0^{\circ}C$, $T_{MAX} = +125^{\circ}C$

* Load and line regulation are specified at constant junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M06/I ELECTRICAL CHARACTERISTICS

(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=11V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	5.75	6	6.25	V
		$I_O=5$ to 350mA $V_I=8$ to 21V	5.7	6	6.3	
Line Regulation	ΔV_O	$I_O=200mA$ $T_J=25^\circ C$			100	mV
		$V_I=8$ to 25V $V_I=9$ to 25V			50	
Load Regulation	ΔV_O	$I_O=5mA$ to 0.5A, $T_J=25^\circ C$			120	mV
		$I_O=5mA$ to 200mA, $T_J=25^\circ C$			60	
Quiescent Current	I_Q	$T_J=25^\circ C$		4.0	6	mA
Quiescent Current Change	ΔI_Q	$I_O=5mA$ to 350mA			0.5	mA
		$I_O=200mA$ $V_I=9$ to 25V			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O=5mA$ $T_J=0$ to 125°C		- 0.5		mV/°C
Output Noise Voltage	V_N	$f=10Hz$ to 100KHz		45		μV
Ripple Rejection	RR	$f=120Hz$, $I_O=300mA$ $V_I=9$ to 19V	59			dB
Dropout Voltage	V_D	$T_J=25^\circ C$, $I_O=500mA$		2		V
Short Circuit Current	I_{SC}	$T_J=25^\circ C$, $V_I=35V$		300		mA
Peak Current	I_{PK}	$T_J=25^\circ C$		700		mA

* T_{MIN}

LM78MXXI: $T_{MIN}=-40^\circ C$

LM78MXX: $T_{MIN}=0^\circ C$

* Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M08/I ELECTRICAL CHARACTERISTICS(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=14V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	7.7	8	8.3	V
		$I_O = 5$ to $350mA$ $V_I = 10.5$ to $23V$	7.6	8	8.4	
Line Regulation	ΔV_O	$I_O = 200mA$ $T_J = 25^\circ C$			100	mV
		$V_I = 10.5$ to $25V$ $V_I = 11$ to $25V$			50	
Load Regulation	ΔV_O	$I_O = 5mA$ to $0.5A$, $T_J = 25^\circ C$			160	mV
		$I_O = 5mA$ to $200mA$, $T_J = 25^\circ C$			80	
Quiescent Current	I_Q	$T_J = 25^\circ C$		4.0	6	mA
Quiescent Current Change	ΔI_Q	$I_O = 5mA$ to $350mA$			0.5	mA
		$I_O = 200mA$ $V_I = 10.5$ to $25V$			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O = 5mA$ $T_J = 0$ to $125^\circ C$		- 0.5		mV/ $^\circ C$
Output Noise Voltage	V_N	$f = 10Hz$ to $100KHz$		52		μV
Ripple Rejection	RR	$f = 120Hz$, $I_O = 300mA$ $V_I = 9$ to $19V$	56			dB
Dropout Voltage	V_D	$T_J = 25^\circ C$, $I_O = 500mA$		2		V
Short Circuit Current	I_{SC}	$T_J = 25^\circ C$, $V_I = 35V$		300		mA
Peak Current	I_{PK}	$T_J = 25^\circ C$		700		mA

* T_{MIN} LM78MXXI: $T_{MIN}=-40^\circ C$ LM78MXX: $T_{MIN}=0^\circ C$ * Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M10/I ELECTRICAL CHARACTERISTICS(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=17V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	9.6	10	10.4	V
		$I_O = 5$ to $350mA$ $V_I = 12.5$ to $25V$	9.5	10	10.5	
Line Regulation	ΔV_O	$I_O = 200mA$ $T_J = 25^\circ C$			100	mV
		$V_I = 12.5$ to $25V$ $V_I = 13$ to $25V$			50	
Load Regulation	ΔV_O	$I_O = 5mA$ to $0.5A$, $T_J = 25^\circ C$			200	mV
		$I_O = 5mA$ to $200mA$, $T_J = 25^\circ C$			100	
Quiescent Current	I_Q	$T_J=25^\circ C$		4.1	6	mA
Quiescent Current Change	ΔI_Q	$I_O = 5mA$ to $350mA$			0.5	mA
		$I_O = 200mA$ $V_I = 12.5$ to $25V$			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O = 5mA$ $T_J = 0$ to $125^\circ C$		- 0.5		mV/ $^\circ C$
Output Noise Voltage	V_N	$f = 10Hz$ to $100KHz$		65		μV
Ripple Rejection	RR	$f = 120Hz$, $I_O = 300mA$ $V_I = 13$ to $23V$	55			dB
Dropout Voltage	V_D	$T_J = 25^\circ C$, $I_O = 500mA$		2		V
Short Circuit Current	I_{SC}	$T_J = 25^\circ C$, $V_I = 35V$		300		mA
Peak Current	I_{PK}	$T_J = 25^\circ C$		700		mA

* T_{MIN} LM78MXXI: $T_{MIN}=-40^\circ C$ LM78MXX: $T_{MIN}=0^\circ C$ * Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M12/I ELECTRICAL CHARACTERISTICS(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=19V$, unless otherwise specified, $C_I = 0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J = 25^\circ C$	11.5	12	12.5	V
		$I_O = 5$ to $350mA$ $V_I = 14.5$ to $27V$	11.5	12	12.6	
Lines Regulation	ΔV_O	$I_O = 200mA$ $T_J = 25^\circ C$			100	mV
		$V_I = 14.5$ to $30V$ $V_I = 16$ to $30V$			50	
Load Regulation	ΔV_O	$I_O = 5mA$ to $0.5A$, $T_J = 25^\circ C$			240	mV
		$I_O = 5mA$ to $200mA$, $T_J = 25^\circ C$			120	
Quiescent Current	I_Q	$T_J = 25^\circ C$		4.1	6	mA
Quiescent Current Change	ΔI_Q	$I_O = 5mA$ to $350mA$			0.5	mA
		$I_O = 200mA$ $V_I = 14.5$ to $30V$			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O = 5mA$ $T_J = 0$ to $125^\circ C$		- 0.5		mV/°C
Output Noise Voltage	V_N	$f = 10Hz$ to $100KHz$		75		μV
Ripple Rejection	RR	$f = 120Hz$, $I_O = 300mA$ $V_I = 15$ to $25V$	55			dB
Dropout Voltage	V_D	$T_J = 25^\circ C$, $I_O = 500mA$		2		V
Short Circuit Current	I_{SC}	$T_J = 25^\circ C$, $V_I = 35V$		300		mA
Peak Current	I_{PK}	$T_J = 25^\circ C$		700		mA

* T_{MIN} LM78MXXI: $T_{MIN} = -40^\circ C$ LM78MXX: $T_{MIN} = 0^\circ C$ * Load and line regulation are specified at constant junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M15/I ELECTRICAL CHARACTERISTICS

(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=23V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	14.4	15	15.6	V
		$I_O=5$ to 350mA $V_I=17.5$ to 30V	14.25	15	15.75	
Line Regulation	ΔV_O	$I_O=200mA$ $T_J=25^\circ C$			100	mV
		$V_I=17.5$ to 30V $V_I=20$ to 30V			50	
Load Regulation	ΔV_O	$I_O=5mA$ to 0.5A, $T_J=25^\circ C$			300	mV
		$I_O=5mA$ to 200mA, $T_J=25^\circ C$			150	
Quiescent Current	I_Q	$T_J=25^\circ C$		4.1	6	mA
Quiescent Current Change	ΔI_Q	$I_O=5mA$ to 350mA			0.5	mA
		$I_O=200mA$ $V_I=17.5$ to 30V			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O=5mA$ $T_J=0$ to 125°C		- 1		mV/°C
Output Noise Voltage	V_N	$f=10Hz$ to 100KHz		100		μV
Ripple Rejection	RR	$f=120Hz$, $I_O=300mA$ $V_I=18.5$ to 28.5V	54			dB
Dropout Voltage	V_D	$T_J=25^\circ C$, $I_O=500mA$		2		V
Short Circuit Current	I_{SC}	$T_J=25^\circ C$, $V_I=35V$		300		mA
Peak Current	I_{PK}	$T_J=25^\circ C$		700		mA

* T_{MIN}

LM78MXXI: $T_{MIN}=-40^\circ C$

LM78MXX: $T_{MIN}=0^\circ C$

* Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M18/I ELECTRICAL CHARACTERISTICS(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=26V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	17.3	18	18.7	V
		$I_O=5$ to 350mA $V_I=20.5$ to 33V	17.1	18	18.9	
Line Regulation	ΔV_O	$I_O=200mA$ $T_J=25^\circ C$			100	mV
		$V_I=21$ to 33V $V_I=24$ to 33V			50	
Load Regulation	ΔV_O	$I_O=5mA$ to 0.5A, $T_J=25^\circ C$			360	mV
		$I_O=5mA$ to 200mA, $T_J=25^\circ C$			180	
Quiescent Current	I_Q	$T_J=25^\circ C$		4.2	6	mA
Quiescent Current Change	ΔI_Q	$I_O=5mA$ to 350mA			0.5	mA
		$I_O=200mA$ $V_I=21$ to 33V			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O=5mA$ $T_J=0$ to 125°C		- 1.1		mV/°C
Output Noise Voltage	V_N	$f=10Hz$ to 100KHz		100		μV
Ripple Rejection	RR	$f=120Hz$, $I_O=300mA$ $V_I=22$ to 32V	53			dB
Dropout Voltage	V_D	$T_J=25^\circ C$, $I_O=500mA$		2		V
Short Circuit Current	I_{SC}	$T_J=25^\circ C$, $V_I=35V$		300		mA
Peak Current	I_{PK}	$T_J=25^\circ C$		700		mA

* T_{MIN} LM78MXXI: $T_{MIN}=-40^\circ C$ LM78MXX: $T_{MIN}=0^\circ C$ * Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M20/I ELECTRICAL CHARACTERISTICS(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=29V$, unless otherwise specified, $C_I=0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J=25^\circ C$	19.2	20	20.8	V
		$I_O=5$ to 350mA $V_I=23$ to 35V	19	20	21	
Line Regulation	ΔV_O	$I_O=200mA$ $T_J=25^\circ C$			100	mV
		$V_I=23$ to 35V $V_I=24$ to 35V			50	
Load Regulation	ΔV_O	$I_O=5mA$ to 0.5A, $T_J=25^\circ C$			400	mV
		$I_O=5mA$ to 200mA, $T_J=25^\circ C$			200	
Quiescent Current	I_Q	$T_J=25^\circ C$		4.2	6	mA
Quiescent Current Change	ΔI_Q	$I_O=5mA$ to 350mA			0.5	mA
		$I_O=200mA$ $V_I=23$ to 35V			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O=5mA$ $T_J=0$ to 125°C		- 1.1		mV/°C
Output Noise Voltage	V_N	$f=10Hz$ to 100KHz		110		μV
Ripple Rejection	RR	$f=120Hz$, $I_O=300mA$ $V_I=24$ to 34V	53			dB
Dropout Voltage	V_D	$T_J=25^\circ C$, $I_O=500mA$		2		V
Short Circuit Current	I_{SC}	$T_J=25^\circ C$, $V_I=35V$		300		mA
Peak Current	I_{PK}	$T_J=25^\circ C$		700		mA

* T_{MIN} LM78MXXI: $T_{MIN}=-40^\circ C$ LM78MXX: $T_{MIN}=0^\circ C$ * Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

LM78M24/I ELECTRICAL CHARACTERISTICS

(Refer to the test circuits, T_{MIN} T_J 125°C, $I_O=350mA$, $V_I=33V$, unless otherwise specified, $C_I = 0.33\mu F$, $C_O=0.1\mu F$)

Characteristic	Symbol	Test Conditions	Min	Typ	Max	Unit
Output Voltage	V_O	$T_J = 25^\circ C$	23	24	25	V
		$I_O = 5$ to $350mA$ $V_I = 27$ to $38V$	22.8	24	25.2	
Line Regulation	ΔV_O	$I_O = 200mA$ $T_J = 25^\circ C$			100	mV
		$V_I = 27$ to $38V$ $V_I = 28$ to $38V$			50	
Load Regulation	ΔV_O	$I_O = 5mA$ to $0.5A$, $T_J = 25^\circ C$			480	mV
		$I_O = 5mA$ to $200mA$, $T_J = 25^\circ C$			240	
Quiescent Current	I_Q	$T_J = 25^\circ C$		4.2	6	mA
Quiescent Current Change	ΔI_Q	$I_O = 5mA$ to $350mA$			0.5	mA
		$I_O = 200mA$ $V_I = 27$ to $38V$			0.8	
Output Voltage Drift	$\frac{\Delta V_O}{\Delta T}$	$I_O = 5mA$ $T_J = 0$ to $125^\circ C$		- 1.2		mV/°C
Output Noise Voltage	V_N	$f = 10Hz$ to $100KHz$		170		μV
Ripple Rejection	RR	$f = 120Hz$, $I_O = 300mA$ $V_I = 28$ to $38V$	50			dB
Dropout Voltage	V_D	$T_J = 25^\circ C$, $I_O = 500mA$		2		V
Short Circuit Current	I_{SC}	$T_J = 25^\circ C$, $V_I = 35V$		300		mA
Peak Current	I_{PK}	$T_J = 25^\circ C$		700		mA

* T_{MIN}

LM78MXXI: $T_{MIN} = -40^\circ C$

LM78MXX: $T_{MIN} = 0^\circ C$

* Load and line regulation are specified at constant, junction temperature. Change in V_O due to heating effects must be taken into account separately. Pulse testing with low duty is used.

APPLICATION CIRCUIT

Fig. 1 Fixed output regulator

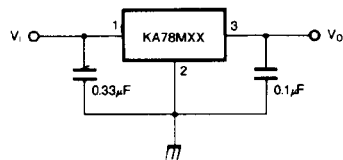
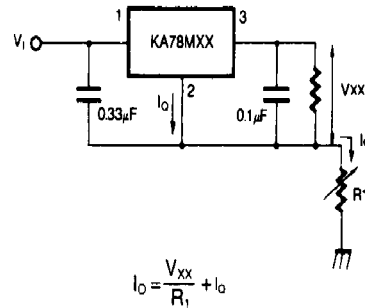


Fig. 2 Constant current regulator



Notes:

- (1) To specify an output voltage, substitute voltage value for "XX".
- (2) Although no output capacitor is needed for stability, it does improve transient response.
- (3) Required if regulator is located an appreciable distance from power supply filter.

Fig. 3 Circuit for Increasing output voltage

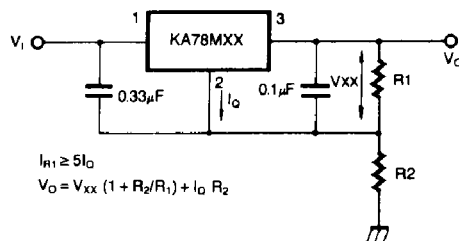


Fig. 4 Adjustable output regulator (7 to 30V)

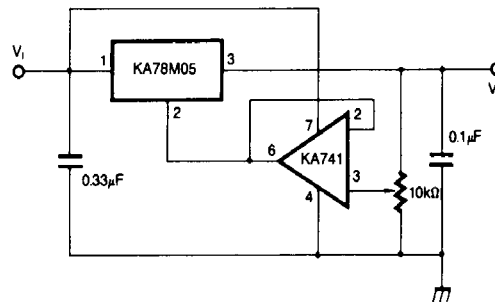
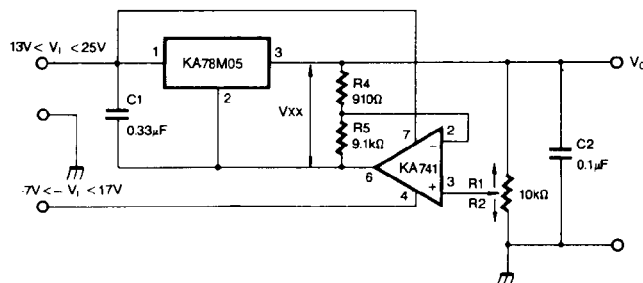


Fig. 5 0.5 to 10V Regulator



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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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